参考資料

COSEL

April 15, 2009
OS DESIGN DEPT.2

SUT3 Series EMI／EMS Test results

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No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	O.k.
2	Radiated emission	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	O.k.
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4) Contact discharge voltage 4[kV] (EN61000-4-2 Level 2) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.k.
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4)Testing field strength 10[V/m] (EN61000-4-3 Level 3) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.K.
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.K.
6	Surge immunity test (EN61000-4-5)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10℃ (4) Test voltage Line to line 2[kV] (Level 3) (5) Testing circuitry Fig.3	(1)The power supply is not stop. (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	O.K.

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○ Testing circuitry

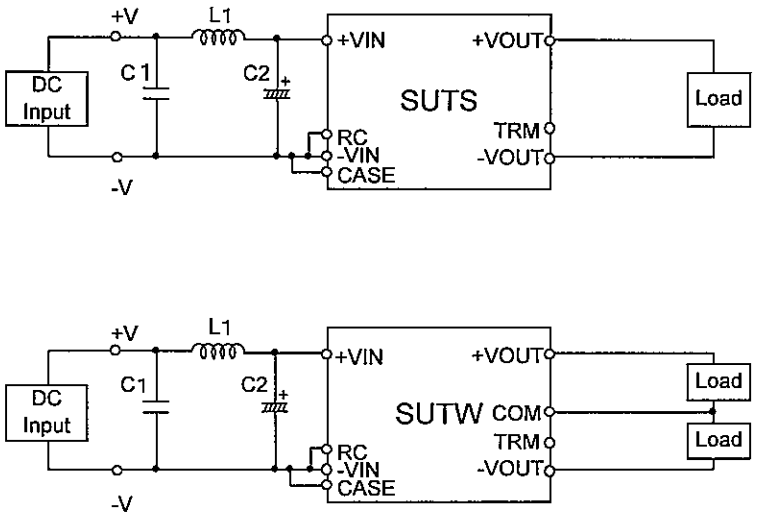

Fig.1 Testing circuitry

SUT□305

L1：	2.2μH		CY3H-2R2	(KORIN ELECTRONICS)
C1：	16V	1μF	C2012JB1C105K	(TDK)
C2：	16V	220μF	UPW1C221M	(NICHICON)

SUT□312

L1：	4.7μH		CY3H-4R7	(KORIN ELECTRONICS)
C1：	25V	1μF	C2012JB1E105K	(TDK)
C2：	25V	100μF	UPW1E101M	(NICHICON)

SUT□324

L1：	10μH		CY3H-100	(KORIN ELECTRONICS)
C1：	50V	0.47μF	C2012JB1H474K	(TDK)
C2：	50V	47μF	UPW1H470M	(NICHICON)

SUT□348

L1：	10μH		CY3H-100	(KORIN ELECTRONICS)
C1：	100V	0.47μF	C3216JB2A474K	(TDK)
C2：	100V	22μF	UPW2A220M	(NICHICON)

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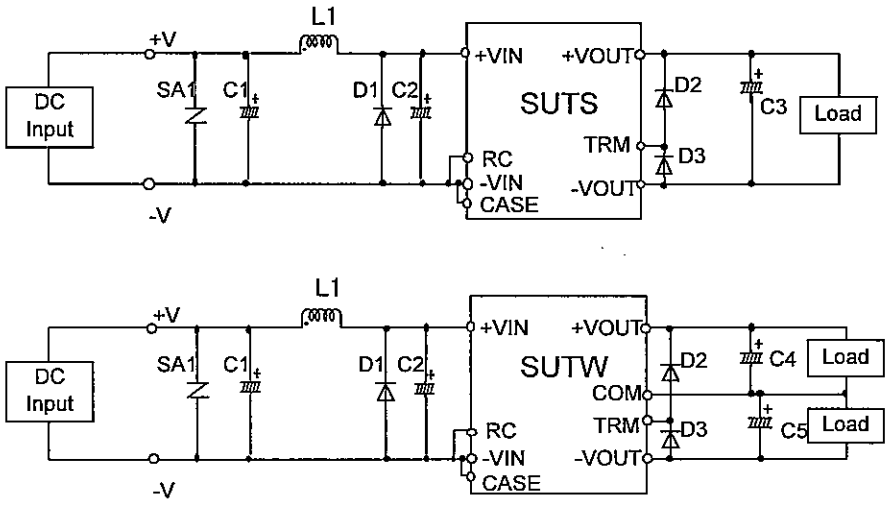

Fig.2 Testing circuritry

SUT□305

C1	:	25V	1000μF	UPW1E102M	(NICHICON)
C2	:	16V	220μF	UPW1C221M	(NICHICON)
SA1	:	18V	ERZV10D180	(MATSUSHITA ELECTRONIC)	
L1	:	2.2μH	CY3H-2R2	(KORIN ELECTRONICS)	

SUT□312

C1	:	25V	470μF	UPW1E471M	(NICHICON)
C2	:	25V	100μF	UPW1E101M	(NICHICON)
SA1	:	27V	ERZV10D270	(MATSUSHITA ELECTRONIC)	
L1	:	4.7μH	CY3H-4R7	(KORIN ELECTRONICS)	

SUT□324

C1	:	50V	100μF	UPW1H101M	(NICHICON)
C2	:	50V	47μF	UPW1H470M	(NICHICON)
SA1	:	47V	ERZV10D470	(MATSUSHITA ELECTRONIC)	
L1	:	10μH	CY3H-100	(KORIN ELECTRONICS)	

SUT□348

C1	:	100V	33μF	UPW2A330M	(NICHICON)
C2	:	100V	22μF	UPW2A220M	(NICHICON)
SA1	:	100V	ERZV10D101	(MATSUSHITA ELECTRONIC)	
L1	:	10μH	CY3H-100	(KORIN ELECTRONICS)	

D1	:		3A	200V	ERD32-02	(FUJI ELECTRIC)
D2,D3	:		1A	100V	S5566B	(TOSHIBA)
C3	:	SUTS305	25V	220μF	UPW1E221M	(NICHICON)
C4,C5	:	SUTW305	25V	100μF	UPW1E101M	(NICHICON)

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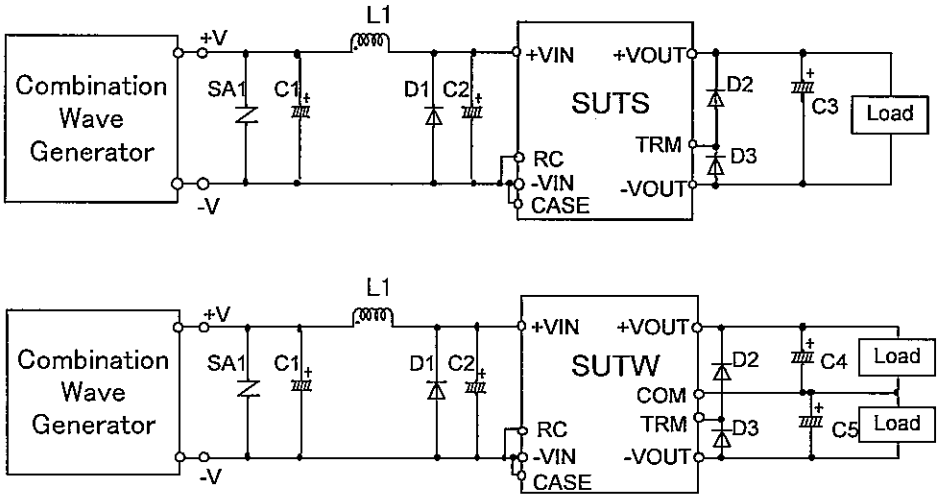

Fig.3 Surge immunity testing circuitry

SUT□305

C1	:	25V	1000μF	UPW1E102M	(NICHICON)
C2	:	16V	220μF	UPW1C221M	(NICHICON)
SA1	:	18V	ERZV10D180	(MATSUSHITA ELECTRONIC)	
L1	:	2.2μH	CY3H-2R2	(KORIN ELECTRONICS)	

SUT□312

C1	:	25V	470μF	UPW1E471M	(NICHICON)
C2	:	25V	100μF	UPW1E101M	(NICHICON)
SA1	:	27V	ERZV10D270	(MATSUSHITA ELECTRONIC)	
L1	:	4.7μH	CY3H-4R7	(KORIN ELECTRONICS)	

SUT□324

C1	:	50V	100μF	UPW1H101M	(NICHICON)
C2	:	50V	47μF	UPW1H470M	(NICHICON)
SA1	:	47V	ERZV10D470	(MATSUSHITA ELECTRONIC)	
L1	:	10μH	CY3H-100	(KORIN ELECTRONICS)	

SUT□348

C1	:	100V	33μF	UPW2A330M	(NICHICON)
C2	:	100V	22μF	UPW2A220M	(NICHICON)
SA1	:	100V	ERZV10D101	(MATSUSHITA ELECTRONIC)	
L1	:	10μH	CY3H-100	(KORIN ELECTRONICS)	

D1	:		3A	200V	ERD32-02	(FUJI ELECTRIC)
D2,D3	:		1A	100V	S5566B	(TOSHIBA)
C3	:	SUTS305	25V	220μF	UPW1E221M	(NICHICON)
C4,C5	:	SUTW305	25V	100μF	UPW1E101M	(NICHICON)